

# **International Technology Roadmap for Semiconductors**

## **Assembly and Packaging 2006**



# Assembly and Packaging Roadmap 2006 Participants

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# ITRS A&P Chapter Organization

- Scope
- Difficult Challenges
- Technical Requirements
- Infrastructure Challenges
- Potential Solutions
- Tables



# Assembly and Packaging Roadmap 2006

- Packaging has become the limiting element in system cost and performance
- The Assembly and packaging role is expanding to include system level integration functions.
- As traditional Moore's law scaling become more difficult innovation in assembly and packaging innovation can take up the slack.



# Computing System performance increase continues

**Example: Game Console  
from this...**



Mini Football video game

Circa: 1990s

to this...



July 12, 2006

# Assembly and Packaging Emerging as Limiting Factor for Cost and Performance

- Consumers now drive more than half of integrated circuit revenue
- Assembly and Packaging technology is a primary differentiator for consumer electronics
- These factors are driving an unprecedented pace of innovation in:
  - New Materials
  - New Technologies
  - New Systems Integration



# Assembly and Packaging

**The pace of change in several areas is faster than anticipated**

- System in a package (SiP) has become the structure of choice for many consumer products with new requirements for package design, materials, processing and test access
- Wafer thinning has progressed to a level requiring special handling and assembly processes
- Stacked die package layer count is increasing rapidly requiring new methods for bonding, testing, etc.

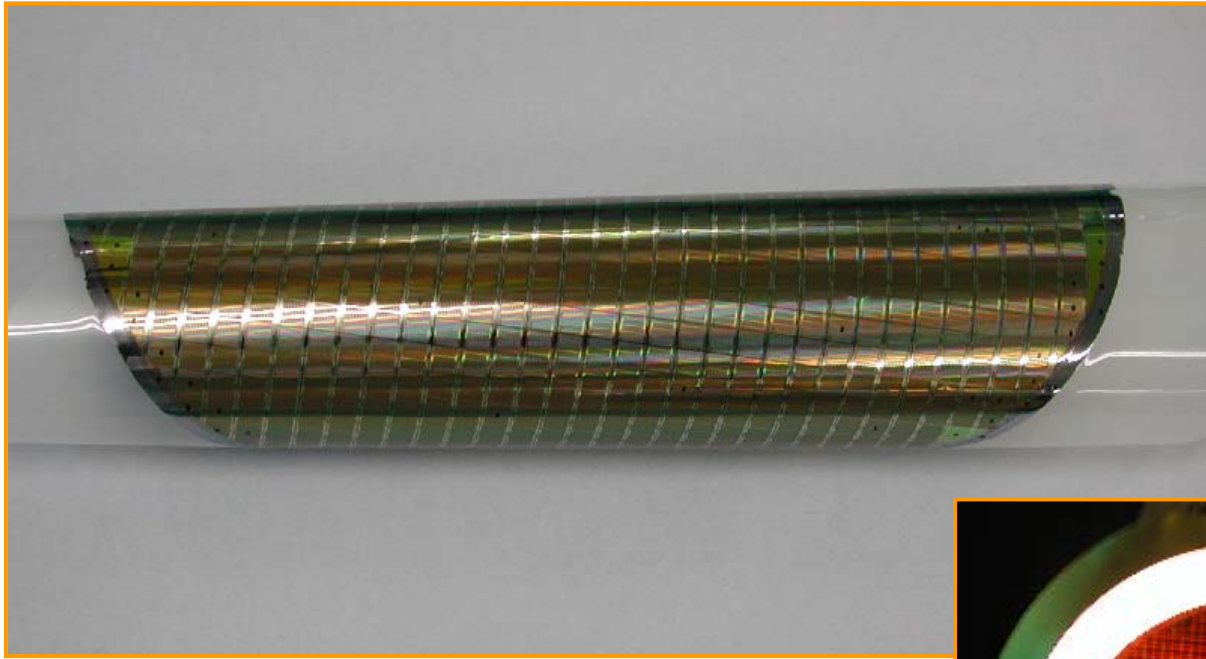


# New Packaging Technologies

- Thinned wafers
- 3D systems integration
- Wafer level packaging
- Bio-chips
- Integrated optics
- Embedded/integrated active and passive devices
- MEMS
- Printable circuits
  - Semiconductors
  - Light emitters
  - RF
  - Interconnect
- Flexible (wearable) electronics



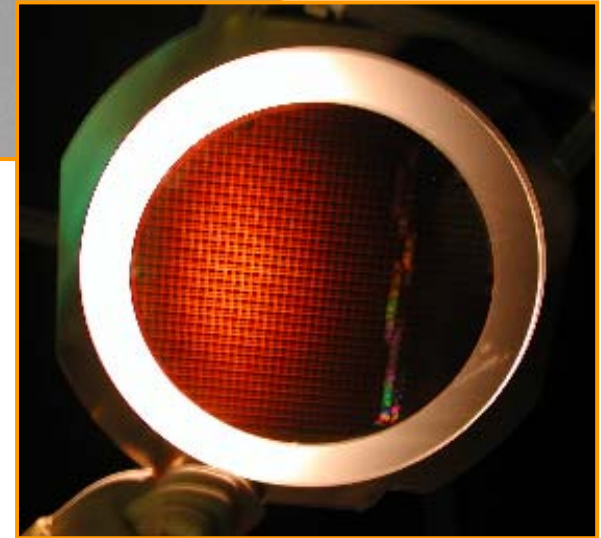
# Thinned Wafers/Die



(a) Rolled Wafer

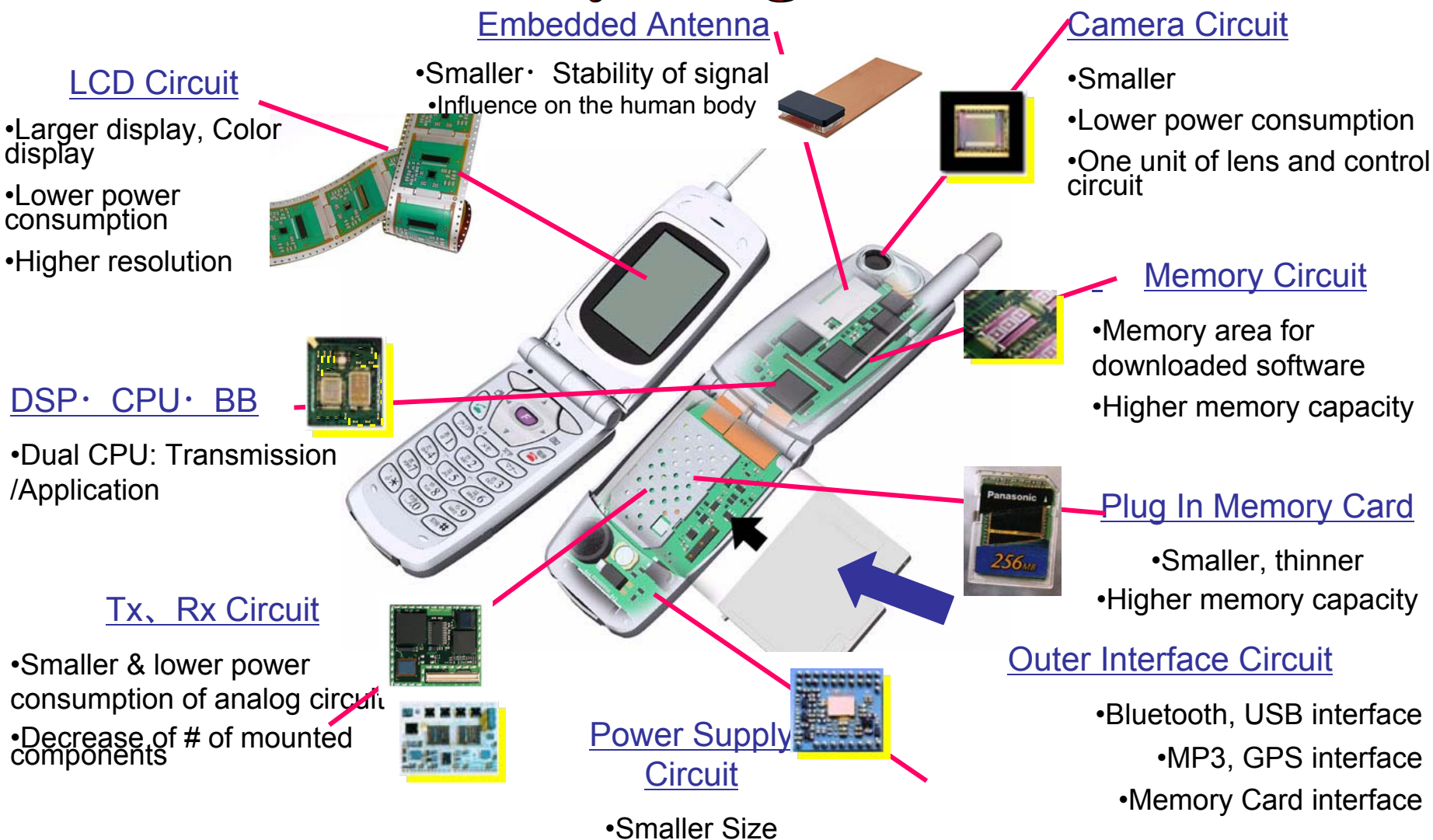
**10 $\mu$ m Thickness Wafer**

(b) Light  
Transparency



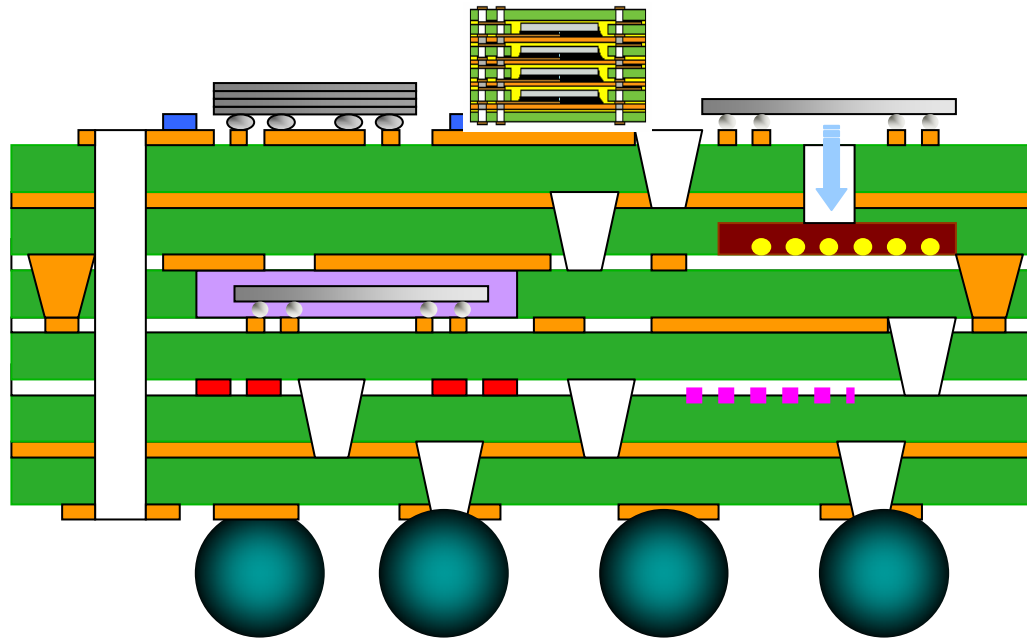
# Systems Integration in the Cellular Phone

## It is not only integrated circuits



# SiP: Multi-level System Integration

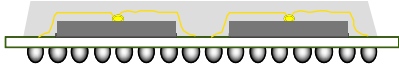
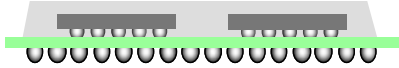

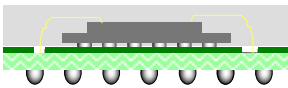
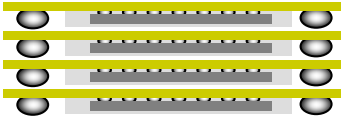

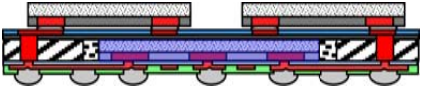
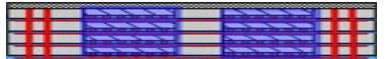
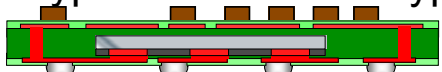
SiP may include SoC and other traditional packages



Packages may include:

- Sub-system packages
- Stacked thin packages containing passives and active chips
- Mechanical, optical and other non electrical functions
- Complete systems or sub-systems with embedded components
- Bare die

# Categories of SiP

Horizontal Placement		 <p>Wire Bonding Type</p>	 <p>Flip Chip Type</p>	
Stacked Structure	Interposer Type	 <p>Wire Bonding Type</p>	 <p>Wire Bonding + Flip Chip Type</p>	 <p>Flip Chip Type</p>
	Interposer-less Type	 <p>Terminal Through Via Type</p>		
Embedded Structure		 <p>Chip (WLP) Embedded + Chip on Surface Type</p>	 <p>3D Chip Embedded Type</p>	 <p>WLP Embedded + Chip on Surface Type</p>



# Assembly and Packaging

**There are significant revisions to tables**

## ■ Difficult Challenges

- Pb free transition presents cost, reliability and process compatibility problems that are not resolved
- A new generation of DFM and DFT will be required for complex SiP and SoC packaging
- Stress induced changes in electrical properties for very thin die
- Reliability for through wafer vias and die layer bonding
- Warpage control for stacked die
- Interconnect for nano-scale structures
- Self assembly for very small die



# Significant Table Revisions

## Continued

- Many new Materials are required for the emerging package requirements:
  - Improved thermal conductivity for dielectrics and materials interfaces
  - Molding compounds compatible with copper and other new materials
  - Improved resistance to electromigration as temperature and current density continue to rise
  - Dielectrics with improved fracture toughness and interfacial adhesion
  - Green materials that meet regulatory, cost and reliability requirements



# New Materials

**Most, if not all, packaging materials will change within this decade**

- Cu interconnect
- Ultra Low k dielectrics
- High k dielectrics
- Organic semiconductors
- Green Materials
  - Pb free
  - Halogen free
  - other



# Assembly and Packaging

## Technical working Group 2006 Focus

We are giving special focus in 2006 to preparation of a white paper titled:

**“The next step in Assembly and Packaging:  
Systems Level Integration”**

### **Objectives of this white paper**

- Catalyze additional SiP chapter for 2007 ITRS issue
- Identify needs and gaps
- Identify new technology trends for future SiP



# **“The next step in Assembly and Packaging: Systems Level Integration”**

## **Introduction & Motivation**

- The basic elements generic to all SiP System level integration applications will be defined.
- Examples will be used from various application areas to show how the basic elements are incorporated into these applications.



# Critical updates to selected sections in preparation for 2007

- Expansion of the section on handling and packaging of extremely thin die
- Expanded treatment of sensors in cooperation with iNEMI



**3D Packaging increases Performance Density  
and enables system level integration**

**Thank You**

